#### Application/Control No. Applicant(s)/Patent Under Reexamination 09/252.925 OHNISHI ET AL. Notice of References Cited Examiner **Art Unit** Page 1 of 1 2662 Hanh Nguyen **U.S. PATENT DOCUMENTS Document Number** Date Classification Country Number-Kind Code MM-YYYY US-6567177 B2 A 05-2003 Matsuyama 358/1.14 В US-5546388 08-1996 Lin 370/389 C US-5373550 12-1994 Campbell et al. 379/100 US-5987501 D 11-1999 Hamilton et al. 709/203 E US-F US-G US-Н US-US-J US-Κ US-US-L

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